

Resource Summary Report

Generated by [RRID](#) on Aug 5, 2026

Rigaku: MFM310

RRID:SCR_020440

Type: Tool

Proper Citation

Rigaku: MFM310 (RRID:SCR_020440)

Resource Information

URL: <https://www.rigaku.com/products/semi/mfm310>

Proper Citation: Rigaku: MFM310 (RRID:SCR_020440)

Description: X-ray metrology tool to perform high throughput measurements on product and blanket wafers ranging from ultrathin single layer films to multilayer stacks.

Resource Type: instrument resource

Keywords: Rigaku, Semiconductor Metrology, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: Rigaku: MFM310

Resource ID: SCR_020440

Alternate IDs: Model_Number_MFM310

Record Creation Time: 20220129T080350+0000

Record Last Update: 20260801T190657+0000

Ratings and Alerts

No rating or validation information has been found for Rigaku: MFM310.

No alerts have been found for Rigaku: MFM310.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.